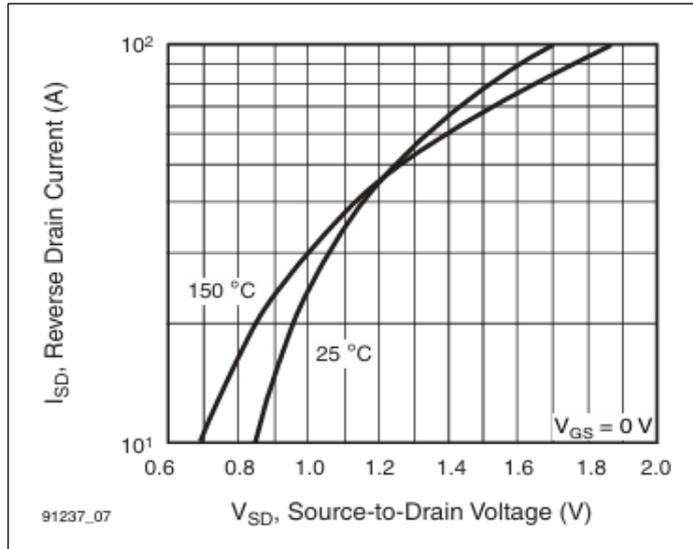


MOSFET Datasheet

SPECIFICATIONS $T_J = 25^\circ \text{C}$, unless otherwise noted						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Static						
Drain-source breakdown voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	500	-	-	V
VDS temperature coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$	-	0.63	-	V/ $^\circ\text{C}$
Gate-source threshold voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	-	4.0	V
Gate-source leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	25	μA
		$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ \text{C}$	-	-	250	
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$ $I_D = 12 \text{ A}$	-	-	0.27	Ω
Forward transconductance	g_{fs}	$V_{DS} = 50 \text{ V}, I_D = 12 \text{ A}$	13	-	-	S
Dynamic						
Input capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1.0 \text{ MHz}$	-	4200	-	pF
Output capacitance	C_{oss}		-	870	-	pF
Reverse transfer capacitance	C_{rss}		-	350	-	pF
Total gate charge	Q_g	$V_{GS} = 10 \text{ V}$ $I_D = 20 \text{ A}$ $V_{DS} = 400 \text{ V}$	-	-	210	nC
Gate-source charge	Q_{gs}		-	-	29	nC
Gate-drain charge	Q_{gd}		-	-	110	nC
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 250 \text{ V}$ $I_D = 20 \text{ A}$ $R_G = 4.3 \Omega$ $R_D = 13 \Omega$	-	18	-	ns
Rise time	t_r		-	59	-	ns
Turn-off delay time	$t_{d(off)}$		-	110	-	ns
Fall time	t_f		-	58	-	ns
Drain-Source Body Diode Characteristics						
Body diode voltage	V_{SD}	$T_J = 25^\circ \text{C}, I_S = 20 \text{ A}, V_{GS} = 0 \text{ V}$	-	-	1.8	V
Body diode reverse recovery time	t_{rr}	$T_J = 25^\circ \text{C}, I_F = 20 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$	-	570	860	ns
Body diode reverse recovery charge	Q_{rr}		-	5.7	8.6	μC

Typical Source-Drain Diode Forward Voltage



Typical Capacitance vs. Drain-to-Source Voltage

